

MK
Computer Architecture
A Quantitative Approach, Fifth Edition



Chapter 1

Fundamentals of Quantitative Design and Analysis Part II

*These slides are based on the slides provided by the publisher.
The slides will be modified, annotated, explained on the board, and sometimes corrected in the class*

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Transistors and Wires

Trends in Technology

- Feature size
 - Minimum size of transistor or wire in x or y dimension
 - 10 microns in 1971 to .032 microns in 2011 (intel 14nm)
 - Transistor performance scales linearly
 - Wire delay does not improve with feature size!
 - Integration density scales quadratically

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Power and Energy

Trends in Power and Energy

- Problem: Get power in, get power out
- Power vs. Energy: Which is more important?
- Thermal Design Power (TDP)
 - Characterizes sustained power consumption
 - Used as target for power supply and cooling system
 - Lower than peak power, higher than average power consumption
- Clock rate can be reduced dynamically to limit power consumption
- Energy per task is often a better measurement

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Dynamic Energy and Power

- Dynamic energy
 - Transistor switch from 0 → 1 or 1 → 0
 - $\frac{1}{2} \times \text{Capacitive load} \times \text{Voltage}^2$
- Dynamic power
 - $\frac{1}{2} \times \text{Capacitive load} \times \text{Voltage}^2 \times \text{Frequency switched}$
- Reducing clock rate reduces power, not energy

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Power

- Intel 80386 consumed ~ 2 W
- 3.3 GHz Intel Core i7 consumes 130 W
- Heat must be dissipated from 1.5 x 1.5 cm chip
- This is the limit of what can be cooled by air
- Hot spot ?

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Reducing Power

- Techniques for reducing power:
 - Do nothing well
 - Dynamic Voltage-Frequency Scaling
 - Design for typical case: for example PMD are idle most of the time, low power state for DRAM, disks
 - Overclocking, turning off cores

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Static Power

- Static power consumption
 - Current_{static} x Voltage
 - Leakage current (power could be as high as 25-50% of total power consumption) increases with decreasing the transistor size (λ)
 - Scales with number of transistors
 - To reduce: power gating

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Trends in Cost

- Cost driven down by learning curve
 - Yield
- DRAM: price closely tracks cost
- Microprocessors: price depends on volume
 - 10% less for each doubling of volume

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Integrated Circuit Cost

- Integrated circuit

Cost of integrated circuit = $\frac{\text{Cost of die} + \text{Cost of testing die} + \text{Cost of packaging and final test}}{\text{Final test yield}}$

Cost of die = $\frac{\text{Cost of wafer}}{\text{Dies per wafer} \times \text{Die yield}}$

Dies per wafer = $\frac{\pi \times (\text{Wafer diameter})^2}{\text{Die area}} - \frac{\pi \times \text{Wafer diameter}}{\sqrt{2} \times \text{Die area}}$

- Bose-Einstein formula:
Die yield = Wafer yield $\times 1 / (1 + \text{Defects per unit area} \times \text{Die area})^N$
- Defects per unit area = 0.016-0.057 defects per square cm (2010)
- N = process-complexity factor = 11.5-15.5 (40 nm, 2010)

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Integrated Circuit Cost

Wafer Yield

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Manufacturing IC's

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Dependability

Dependability

- Service Level Agreement (SLA) guarantees a certain level of dependability.
- Module reliability
 - Mean time to failure (MTTF)
 - Mean time to repair (MTTR)
 - Mean time between failures (MTBF) = MTTF + MTTR
 - Availability = $MTTF / (MTTF + MTTR)$
- Cost of failure: varies hugely depending on applications

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■ **Example**

- 10 disks 1,000,000-hour MTTF
- 1 ATA controller 500,000-hour MTTF
- 1 Power supply 200,000-hour MTTF
- 1 Fan 200,000-hour MTTF
- 1 ATA cable 1,000,000-hour MTTF

■ Assume lifetimes are exponentially distributed and failures are independent

■ Calculate MTTF

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■ What if we added one extra power supply

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Measuring Performance

- Typical performance metrics:
 - Response time
 - Throughput
- Speedup of X relative to Y
 - $\text{Execution time}_Y / \text{Execution time}_X$
- Execution time
 - Wall clock time: includes all system overheads
 - CPU time: only computation time
- Benchmarks
 - Kernels (e.g. matrix multiply)
 - Toy programs (e.g. sorting)
 - Synthetic benchmarks (e.g. Dhrystone)
 - Benchmark suites (e.g. SPEC06fp, TPC-C)

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Measuring Performance

benchmarks

- Embedded Microprocessor Benchmark Consortium
 - www.eembc.org
 - 41 kernels
- SPEC: Standard Performance Evaluation Corporation
 - www.spec.org
 - Covers many application classes (desktop, SPEC Web, SPECFS)
- TPC: Transaction Processing Council
 - www.tpc.org
 - Database transactions

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Reporting Performance

- Many programs, how can we capture performance using a single number?

	P1	P2	P3
Machine-A	10	8	25
Machine-B	12	9	20
Machine-C	8	8	30

- Sum of execution time
- Sum of weighted execution time
- Geometric mean of execution time

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Reporting Performance

	machine_A	M/C_B	M/C_C
P1	1sec	10sec	20sec
P2	1000sec	100sec	20sec

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Reporting Performance

- Time = TC × CPI × IC
- Must be reproducible
- Complete description of the computer and compiler flags.
- Usually, compared to a standard machine execution time $SPECRatioA = T_{ref}/T_A$.
- Geometric mean

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Principles of Computer Design

- Different instruction types having different CPIs

$$\text{CPU clock cycles} = \sum_{i=1}^n IC_i \times CPI_i$$

$$\text{CPU time} = \left(\sum_{i=1}^n IC_i \times CPI_i \right) \times \text{Clock cycle time}$$

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Fallacies and Pitfalls

<p>Fallacies</p> <ul style="list-style-type: none"> ■ Multiprocessors are a silver bullet ■ H/W enhancements improve energy consumption or at least energy neutral ■ Misreading MTTF ■ Peak performance tracks observed performance 	<p>Pitfalls</p> <ul style="list-style-type: none"> ■ Falling prey to Amdahl's law ■ A single point of failure ■ Fault detection can lower availability
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